



PATENT
8017-1169

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Toshitsugu SAKAMOTO et al.	Conf. 9950
Application No. 10/536,993	Group 2826
Filed May 31, 2005	Examiner L. Cruz

SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING
THE SAME

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 22, 2007

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the cited documents are made of record on the enclosed PTO Form-1449.

A concise explanation of the relevance of these items is that these references were cited in an Office Action of February 16, 2007 in the corresponding Chinese Application Serial No. 2003801046267. A copy of the Official Action in which they were cited is attached hereto, with An English translation also attached hereto.

Under the provisions of 37 CFR 1.97(e), the undersigned hereby certifies that each item of information contained in this Information Disclosure Statement was first

cited in any communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attorney Docket No.:

8017-1169

Application No.:

10/536,993

Applicant:

Toshitsugu SAKAMOTO et al.

Filing Date:

May 31, 2005

Group Art Unit:

2826

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)
	2001/0025962	10/04/2001	Nakamoto			
	2002/0163079	11/07/2002	Awano			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* English language abstract provided for the Examiner's convenience